

# Resource Summary Report

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## Hitachi: 3400N Environmental Scanning Electron Microscope

RRID:SCR\_020013

Type: Tool

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### Proper Citation

Hitachi: 3400N Environmental Scanning Electron Microscope (RRID:SCR\_020013)

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### Resource Information

**URL:** <https://cmrf.research.uiowa.edu/hitachi-s-3400n>

**Proper Citation:** Hitachi: 3400N Environmental Scanning Electron Microscope (RRID:SCR\_020013)

**Description:** Hitachi S-3400N SEM is a high performance, user-friendly scanning electron microscope. Features include: VP-mode that allows microscopy of wet, oily and non-conductive samples in their natural state without the need of conventional sample preparation.

**Resource Type:** instrument resource

**Keywords:** Hitachi, Environmental Scanning Electron Microscope, Instrument Equipment, USEDit

**Availability:** Commercially available

**Specification URL:** [https://raw.githubusercontent.com/SciCrunch/RRID-Instruments/main/PDF/SCR\\_020013.pdf](https://raw.githubusercontent.com/SciCrunch/RRID-Instruments/main/PDF/SCR_020013.pdf)

**Resource Name:** Hitachi: 3400N Environmental Scanning Electron Microscope

**Resource ID:** SCR\_020013

**Alternate IDs:** Model\_Number\_3400N

**Record Creation Time:** 20220129T080348+0000

**Record Last Update:** 20260725T190922+0000

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### Ratings and Alerts

No rating or validation information has been found for Hitachi: 3400N Environmental Scanning Electron Microscope.

No alerts have been found for Hitachi: 3400N Environmental Scanning Electron Microscope.

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## Data and Source Information

**Source:** [SciCrunch Registry](#)

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## Usage and Citation Metrics

We have not found any literature mentions for this resource.